



UNITED STATES DEPARTMENT OF COMMERCE
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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.
08/857,100	05/15/97	NEVILL	L 660073.555

JOHN C STEWART
SEED AND BARRY
6300 COLUMBIA TOWER
701 FIFTH AVENUE
SEATTLE WA 98104-7092

MM51/0225

EXAMINER
ST CYR, D

ART UNIT	PAPER NUMBER
2876	

DATE MAILED: 02/25/99

Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner of Patents and Trademarks

Office Action Summary

Application No.

08/857,100

Applicant(s)

Leland R. Nevil

Examiner

Daniel H. Cyn
Diane Lee

Group Art Unit

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☒ Responsive to communication(s) filed on Nov 30, 1998

☒ This action is **FINAL**.

☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11; 453 O.G. 213.

A shortened statutory period for response to this action is set to expire 3 month(s), or thirty days, whichever is longer, from the mailing date of this communication. Failure to respond within the period for response will cause the application to become abandoned. (35 U.S.C. § 133). Extensions of time may be obtained under the provisions of 37 CFR 1.136(a).

Disposition of Claims

☒ Claim(s) 1-25 is/are pending in the application.

Of the above, claim(s) _____ is/are withdrawn from consideration.

☐ Claim(s) _____ is/are allowed.

☒ Claim(s) 1-25 is/are rejected.

☐ Claim(s) _____ is/are objected to.

☐ Claims _____ are subject to restriction or election requirement.

Application Papers

☐ See the attached Notice of Draftsperson's Patent Drawing Review, PTO-948.

☐ The drawing(s) filed on _____ is/are objected to by the Examiner.

☒ The proposed drawing correction, filed on Nov 30, 1998 is ☒ approved ☐ disapproved.

☐ The specification is objected to by the Examiner.

☐ The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. § 119

☐ Acknowledgement is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d).

☐ All ☐ Some* ☐ None of the CERTIFIED copies of the priority documents have been
☐ received.

☐ received in Application No. (Series Code/Serial Number) _____.

☐ received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

*Certified copies not received: _____

☐ Acknowledgement is made of a claim for domestic priority under 35 U.S.C. § 119(e).

Attachment(s)

☒ Notice of References Cited, PTO-892

☒ Information Disclosure Statement(s), PTO-1449, Paper No(s). 5

☐ Interview Summary, PTO-413

☐ Notice of Draftsperson's Patent Drawing Review, PTO-948

☐ Notice of Informal Patent Application, PTO-152

--- SEE OFFICE ACTION ON THE FOLLOWING PAGES ---

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DETAILED ACTION

1. Receipt is acknowledged of the Amendment filed on November 30, 1998 in which claims 1-18 were amended and claims 19-25 were added.

Claim Rejections - 35 U.S.C. § 103

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 1-25 are rejected under 35 U.S.C. 103(a) as being unpatentable over Larson et al, US Patent No. 5,360,747 in view of Aurenus.

Larson et al disclose a method for reducing dice testing with on-chip identification comprising: identifying a plurality of dice 100-199, 200-299, and 300-399, including IC chips therein, formed on a common semiconductor substrate (wafer) W1, W2, and W3, wherein each semiconductor includes a plurality of programmable links (ID cells 7). Each die (IC) is programmed through a link (ID cells 7) with a respective electronic identification. The information of each die is stored on file as to form a look up table. (See col. 3, lines 22-52).

Larson et al fail to show or fairly suggest a housing wherein electrical contacts are connected to the housing to provide electrical contact between the integrated circuit and circuitry external the housing and fail to suggest that each integrated circuit includes an optical mark for

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identifying the integrated circuit wherein the mark is identical to the electronic information stored in the programmable link.

Aurenius et al disclose a microlabelling system and method of making thin label. Aurenius et al disclose a microlabel 40 carrying indicia 46 disposed on an individual die 44 during probing and quality control process wherein the indicia contains information related to the specified die (see col. 10, lines 53-63). Aurenius et al show a housing 126 having an optical mark 122 thereon and having electrical contacts connected to the housing to provide electrical contact between the integrate circuit therein and circuitry external the housing (see figure 8). Aurenius et al also disclose that the optical mark on top on the housing carries the information contained on top of the internally-carried die (see col. 13, lines 3-8).

It would have been obvious for a person of ordinary skill in the art to employ the teachings of Larson et al in conjunction with the teaching of Aurenius et al for the purpose to further reduce dice testing. Having an optical mark on the surface of each die would eliminate unnecessary probe testing time because all dice would be coded with the information on the surface of the dice for identification. Such modification would further reduce wafer testing which would reduce wear and tear on the test probe. Therefore, such modification would have been an obvious expedient within the ordinary skill in the art.

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Conclusion

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Tuttle, US Patent No. 5,787,174, discloses a remote identification of interface circuit. Shaw et al, US Patent No. 5,801,067, disclose a method for recording and identifying integrated circuit chips and the like.

5. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire **THREE MONTHS** from the mailing date of this action. In the event a first reply is filed within **TWO MONTHS** of the mailing date of this final action and the advisory action is not mailed until after the end of the **THREE-MONTH** shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than **SIX MONTHS** from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to **Daniel St-Cyr** whose telephone number is **(703) 305-2556**. The examiner can normally be reached between the hours of 7:00AM to 4:30PM Monday thru Thursday and every other Friday (first Friday of the bi-week).

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, **Donald T. Hajec**, can be reached on (703) 308-4075. The fax phone number for this Group is (703)308-5841 or (703) 308-7722.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (703) 308-0956.

DS

Daniel St. Cyr
January 31, 1999

[Signature]

TITLE/LE

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